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Application/Control No.	Applicant(s)/Patent under Reexamination
10/618,302	HONKEN ET AL.
Examiner	Art Unit

Syed Zaidi

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	SEARCHED			
Class	Subclass	Date	Examiner	
370	516	12/6/2007	sz	
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
EAST image and keyword search in USPAT, US-PGPUB, DERWENT, EPO, JPO, and IBM_TDB (please see search history)	12/6/2007	SZ		
nventor :HONKEN ET AL.	12/6/2007	SZ		
(IEEE Xplore Database(http://ieeexplore.ieee.org/Xp lore/DynWel.jsp)	12/6/2007	SZ		
(370/516 370/498 370/496).CCLS (375/362).CCLS.	12/6/2007	SZ		
Consulted with SPE Seema Rao	12/6/2007	SZ		